

The CMS HPK campaign - An overview

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This contribution gives an overview on the campaign to evaluate the planar silicon sensor options for the CMS Tracker Upgrade. This evaluation is done with one industrial supplier, which is capable to provide the large quantity of sensors needed for the Tracker volume at very high quality. Wafers are processed on various materials (FZ, MCz, Epi), with several dopings (n-type, p-type with p-spray and p-stop strip isolation) and thicknesses (50 μ m – 320 μ m). The different structures on the wafers are explained as well as the irradiation procedures and planned measurements.

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